

Resource Summary Report

Generated by [kravitz2](#) on Aug 1, 2026

Anton Paar: NHT3 Nanoindentation Tester

RRID:SCR_024829

Type: Tool

Proper Citation

Anton Paar: NHT3 Nanoindentation Tester (RRID:SCR_024829)

Resource Information

URL: <https://www.anton-paar.com/corp-en/products/details/nanoindentation-tester-nht3/?srsltid=AfmBOoq6DedA15vEkZb-PLCzHLAhmUbyxAtnWW50jyljVyQCds0yZOPP>

Proper Citation: Anton Paar: NHT3 Nanoindentation Tester (RRID:SCR_024829)

Description: Used for testing hardness, elastic modulus, creep and other surface properties at nanometer to micrometer scale. Its range is from 0.1 mN to 500mN with no need to wait to reach thermal stable state, and instrument indentation test can be performed immediately after startup.NHT3 is a versatile, research-grade platform suited for highly customizable mechanical surface testing.

Synonyms: NHT?? Nanoindentation Tester

Resource Type: instrument resource

Keywords: testing hardness, testing elastic modulus, surface properties testing, testing at nanometer to micrometer scale,

Availability: Commercially available

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_024829.pdf

Resource Name: Anton Paar: NHT3 Nanoindentation Tester

Resource ID: SCR_024829

Alternate IDs: Model_Number_NHT3

Old URLs: <https://www.anton-paar.cn/products/details/nanoindentation-tester-nht3/>

Record Creation Time: 20240104T050329+0000

Record Last Update: 20260725T191444+0000

Ratings and Alerts

No rating or validation information has been found for Anton Paar: NHT3 Nanoindentation Tester.

No alerts have been found for Anton Paar: NHT3 Nanoindentation Tester.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We found 1 mentions in open access literature.

Listed below are recent publications. The full list is available at [kravitz2](#) .

Zhang Y, et al. (2024) Penetrating the ultra-tough yeast cell wall with finite element analysis model-aided design of microtools. iScience, 27(4), 109503.